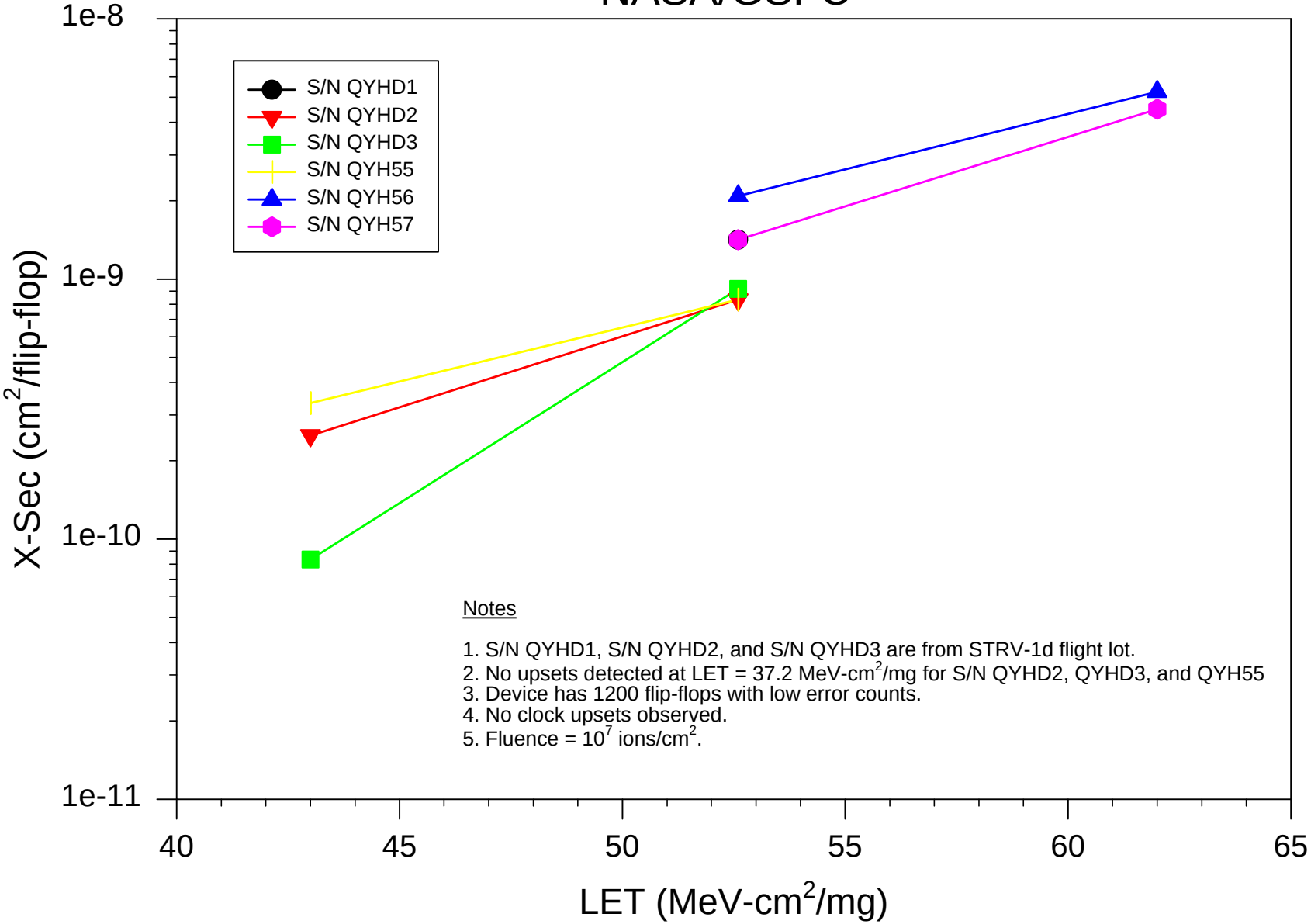
QYH530 SEU Test
One-Mask Parts @ V_{CC} = 5.0VDC
BNL, May 1998
NASA/GSFC



Notes

1. S/N QYHD1, S/N QYHD2, and S/N QYHD3 are from STRV-1d flight lot.
2. No upsets detected at LET = 37.2 MeV-cm^2/mg for S/N QYHD2, QYHD3, and QYH55
3. Device has 1200 flip-flops with low error counts.
4. No clock upsets observed.
5. Fluence = 10^7 ions/cm^2.